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S1	DISLOCATION (S) LEAKAGE	483	<a href="#">Report</a>
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S3	(MISFET OR MOSFET OR NMOS OR PMOS OR FET OR CMOS)	229972	<a href="#">Report</a>
S4	CONCENTRATION (S) IMPURITY	22837	<a href="#">Report</a>
S5	S1 AND S3 AND S4	0	<a href="#">Report</a>
S6	S1 AND S4	2	<a href="#">Report</a>
S7	S1 AND S3	91	<a href="#">Report</a>
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S9	(STRAINED OR STRAIN OR SI OR SIGE)	985945	<a href="#">Report</a>
S10	S8 AND S9	36	<a href="#">Report</a>
S11	(ISOLATION OR INSULATING OR ISULATION) AND (SUBSTRATE OR BASE)	20344	<a href="#">Report</a>
S12	(ISOLATION OR INSULATING OR ISULATION OR DIELECTRIC) AND (SUBSTRATE BASE)	0	<a href="#">Report</a>
S13	S10 AND S11	2	<a href="#">Report</a>
S14	(GATE AND (SOURCE OR DRAIN) AND DISLOCATION AND LEAKAGE AND DEPTH AND CONCENTRATION)	0	<a href="#">Report</a>
S15	(GATE AND (SOURCE OR DRAIN) AND DISLOCATION AND LEAKAGE)	33	<a href="#">Report</a>
S16	(DEPTH OR THICK OR THICKNESS OR GREATER) AND DISLOCATION	12024	<a href="#">Report</a>
S17	S16 AND CONCENTRATION	1071	<a href="#">Report</a>
S18	17 AND S3	3070	<a href="#">Report</a>
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Format  
   
 Number of Records

Show Database Details for:  2: Inspec (1898-present)

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